

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS	:	Jong-Cheol Lee, et al.	ATTY DOCKET NO.	:	8836-223 (ID12244-US)
SERIAL NO.	:	10/748,906	EXAMINER	:	Saqib Javaid Siddiqui
FILED	:	December 30, 2003	ART UNIT	:	2138
TITLE	:	<i>SEMICONDUCTOR MEMORY DEVICE TESTABLE WITH A SINGLE DATA RATE AND/OR DUAL DATA RATE PATTERN IN A MERGED DATA INPUT/OUTPUT PIN TEST MODE</i>			

MAIL STOP: AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

SIR :

In response to the Official Action of November 24, 2006, applicants respectfully request that the above-identified application be amended as follows.

Amendments to the claims are reflected in the Listing of Claims that begins on page 2 of this Amendment.

Amendments to the drawings are set forth on page 6 of this Amendment and include a replacement sheet for FIG. 1.

The Remarks portion begins on page 7 of this Amendment.